

Test Research, Inc. (TRI), a leading test and inspection systems provider for the electronics manufacturing industry, returns to APEX EXPO 2014 with a powerful and cost-effective product lineup that encompasses a full range of solutions for inspecting and testing PCB assemblies. Test Research, Inc. invites you to visit **Booth No. 1271, March 25-27 at Mandalay Bay Convention Center—Las Vegas, Nevada** to view on-site demonstrations of the following systems:



TR7500 SIII 3D AOI

- Total Coverage 2D + multi angle 3D AOI
- True 3D Profile Measurement
- 5 High Resolution Color Cameras
- Fully Automated Easy Programming
- High Performance Design for Automotive and HDI



TR7600LL SII 3D AXI

- High-speed Oversize Inline 3D X-ray Inspection
- Board Size up to 1000 x 660 mm
- BGA, PoP, Press-fit, PTH, QFN, Inspection
- Automated CAD-based or Manual Programming with Auto Tuning
- Multiple Resolutions in One Program
- BlockScan 3D Slice Imaging



TR7700 SIII AOI

- High Speed Multi-Phase Inspection
10 μ m 60 cm²/sec
15 μ m 120 cm²/sec
- Fully Automated Intelligent Programming
- Auto-tuning Intelligent Automated Conveyor System



TR5001T SII TINY ICT

- World's Most Powerful Tiny ICT
- Best Cost Cutting Solution
- Multi-ICT Parallel Testing
- Boundary Scan Test
- Serial Device Programming
- Advanced Analog and Digital Testing with Programmable DUT Power Supplies



TR7550 SII AOI

- High-speed Inline Pre/Post Reflow AOI System
- 5 Camera Inspection:
Top 3CCD & 4 Angled Cameras
- UV Conformal Coating Inspection Option
- RGB Multi-Angled Lighting Control System
- Linear Motor X-Y Table for Vibration Free Accurate Inspection



TR5001 INLINE ICT

- Modular MDA/ICT/FCT System
- Bosch CM Exclusive ICT Solution
- Conforms to SMEMA Standards
- Powerful Boundary Scan Test Solutions
- Easy to Use On-board Programming Software
- Fast Insertion Mechanism



TR7007 SII Plus 3D SPI

- Ultimate 3D SPI Solution
- Industry Leading Inspection Speed
- Super High Resolution and Accuracy
- Ultra Low Bridge Detection
- Smart 5-step Easy Programming
- Closed Loop Integration

YMS LITE

- Defect Image Analysis & Reporting
- SPI, Pre/Post-reflow AOI & AXI Integration
- Centralized Alarm Management